

SPECIAL PROCEDURES SUBMISSION

PATENT

Attorney Docket No. MTI-31607

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

RECEIVED

Applicant : Teck Kheng Lee

FEB 08 2005

Serial No. : 10/050,507

OFFICE OF PETITIONS

Filing Date : January 16, 2002

For : Elimination of RDL Using Tape Base Flip Chip on Flex for Die Stacking

Examiner: THOMPSON, Craig

Group Art Unit: 2813

Confirmation No.: 7687

CERTIFICATION UNDER 37 CFR 1.8(a) and 1.10

I hereby certify that, on the date shown below, this correspondence is being hand-delivered to OFFICE OF PETITIONS at the US Patent and Trademark Office.

Date: February 8, 2005

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INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to 37 C.F.R. §§ 1.56 and 1.97, Applicant submits the information listed on the enclosed Form 1449/PTO for consideration in the above-identified application. No representation is made that a reference is "prior art" within the meaning of 35 U.S.C. §§ 102 and 103.

This Information Disclosure Statement is being filed in conjunction with a Request for Continued Examination (RCE). Accordingly, no fee is due for the consideration of these references.

Return of the enclosed Form 1449 in the next communication to Applicant, showing the citations as initialed and considered, is respectfully requested.

Respectfully submitted,

Kristine M. Strodthoff

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Dated: February 7, 2005, 2005
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Washington, D.C. 20231		ATTY. DOCKET NO. MTI-31607	Serial No. 10/050,507
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT (February 8, 2005)		Applicant Lee, Teck Kheng	Confirmation No. 7687
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U.S. PATENT DOCUMENTS

Examiner Initials	Patent Number	Publication Date	Patentee or Applicant	U.S. Class	Sub-Class
	5,723,347	03/1998	Hirano et al.		
	5,812,378	09/1998	Fjelstad et al.	RECEIVED	
	5,892,271	04/1999	Takeda et al.	FEB 08 2005	
	5,986,460	11/1999	Kawakami	OFFICE OF PETITIONS	
	6,133,072	10/2000	Fjelstad		
	6,208,525	03/2001	Imasu et al.		
	6,271,469	08/2001	Ma et al.		
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	6,634,100	10/2003	Akram et al.		
	6,730,855	05/2004	Bando		
	2001/053563	12/2001	Kim et al.		
	2003/0042595	03/2003	Canella		

Examiner Initials	Date Considered
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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Examiner Initials	Patent Number	Publication Date	Patentee or Applicant	U.S. Class	Sub-Class
	2004/0026773	02/2004	Koon et al.	RECEIVED	
	2004/0212055	10/2004	Exposito et al.	FEB 03 2005	
	2004/0217454	11/2004	Brechignav et al.	OFFICE OF PETITIONS	

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

Examiner Initials	Document Number	Publication Date	Country	Name of Patentee or Applicant	Translation (Yes/No)
	JP 04030456	02/1992	Japan	Yamaguchi	Yes (Abstract)
	EP 0475022 A1	03/1992	EPO	Grube et al.	
	EP 0997942 A2	05/2000	EPO	Horiuchi et al.	
	JP 02000230964	08/2000	Japan	Hikita	Yes (Abstract)

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

Examiner Initials	Non-Patent Document
	Australian Search Report dated 11 Aug 2004 (3 pages).
	Australian Search Report dated 16 Aug 2004 (4 pages).

Examiner Initials	Date Considered
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	